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(54) **CLOCK MULTIPLICATION AND DISTRIBUTION**

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See application file for complete search history.

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(65) **Prior Publication Data**

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(51) **Int. Cl.**

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H04B 1/40	(2015.01)
H03L 7/089	(2006.01)
H03L 7/093	(2006.01)
H03L 7/099	(2006.01)
H03L 7/22	(2006.01)

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(52) **U.S. Cl.**

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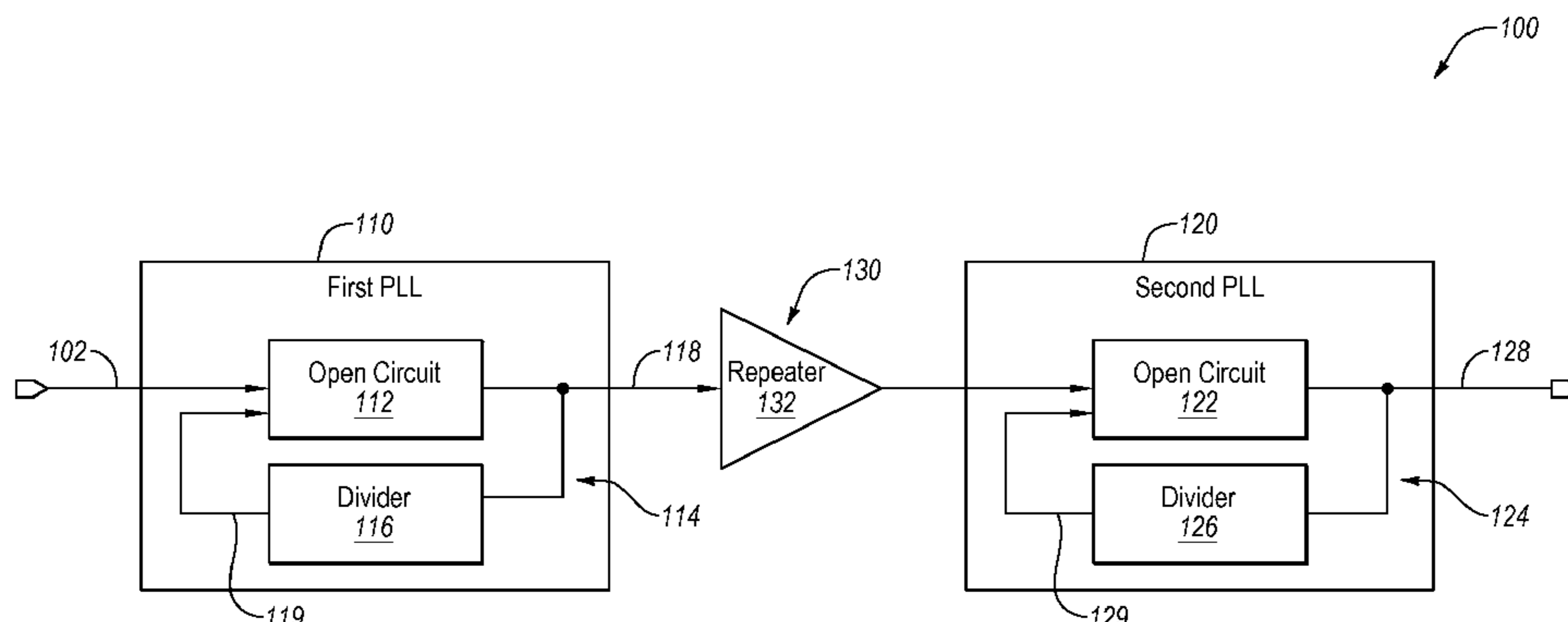
(57) **ABSTRACT**

A clock multiplication and distribution system includes a first phase-lock-loop circuit, a second phase-lock-loop circuit, and a clock distribution network that electrically couples the first phase-lock-loop circuit and the second phase-lock-loop circuit. The first phase-lock-loop circuit may include a first feedback loop that includes a first integer divider circuit and may be configured to generate a first clock using a reference clock. A frequency of the first clock may be greater than a frequency of the reference clock. The second phase-lock-loop circuit may include a second feedback loop that includes a second integer divider circuit and may be configured to generate a second clock using the first clock. A frequency of the second clock may be greater than the frequency of the first clock.

(58) **Field of Classification Search**

CPC G06F 1/10; G06F 1/04; G06F 1/06; G06F 1/12; H03L 7/08; H03L 7/0891; H03L 7/093; H03L 7/087; H03L 7/18; H03L 7/0898; H03L 7/099; H03L 7/22; H03L 2207/06; H04L 7/0331; H04L 7/033; H04B 1/40

16 Claims, 10 Drawing Sheets



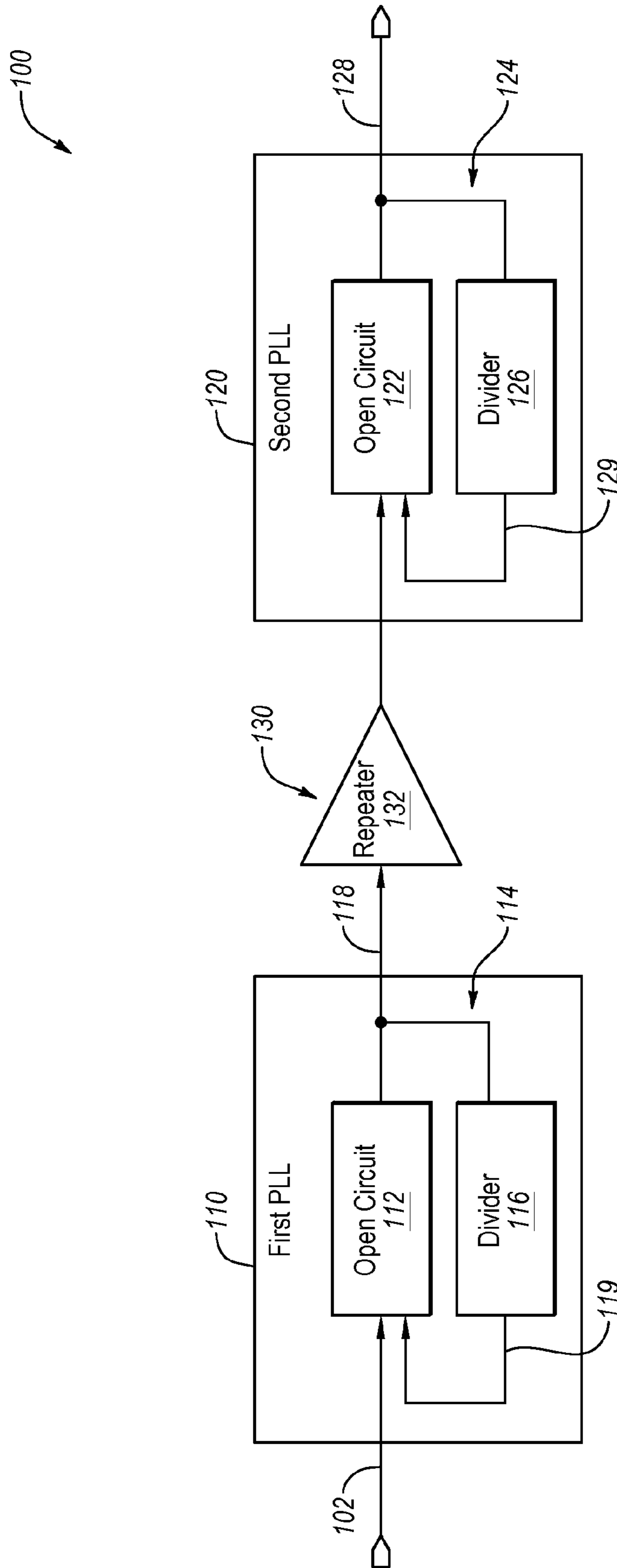


Fig. 1

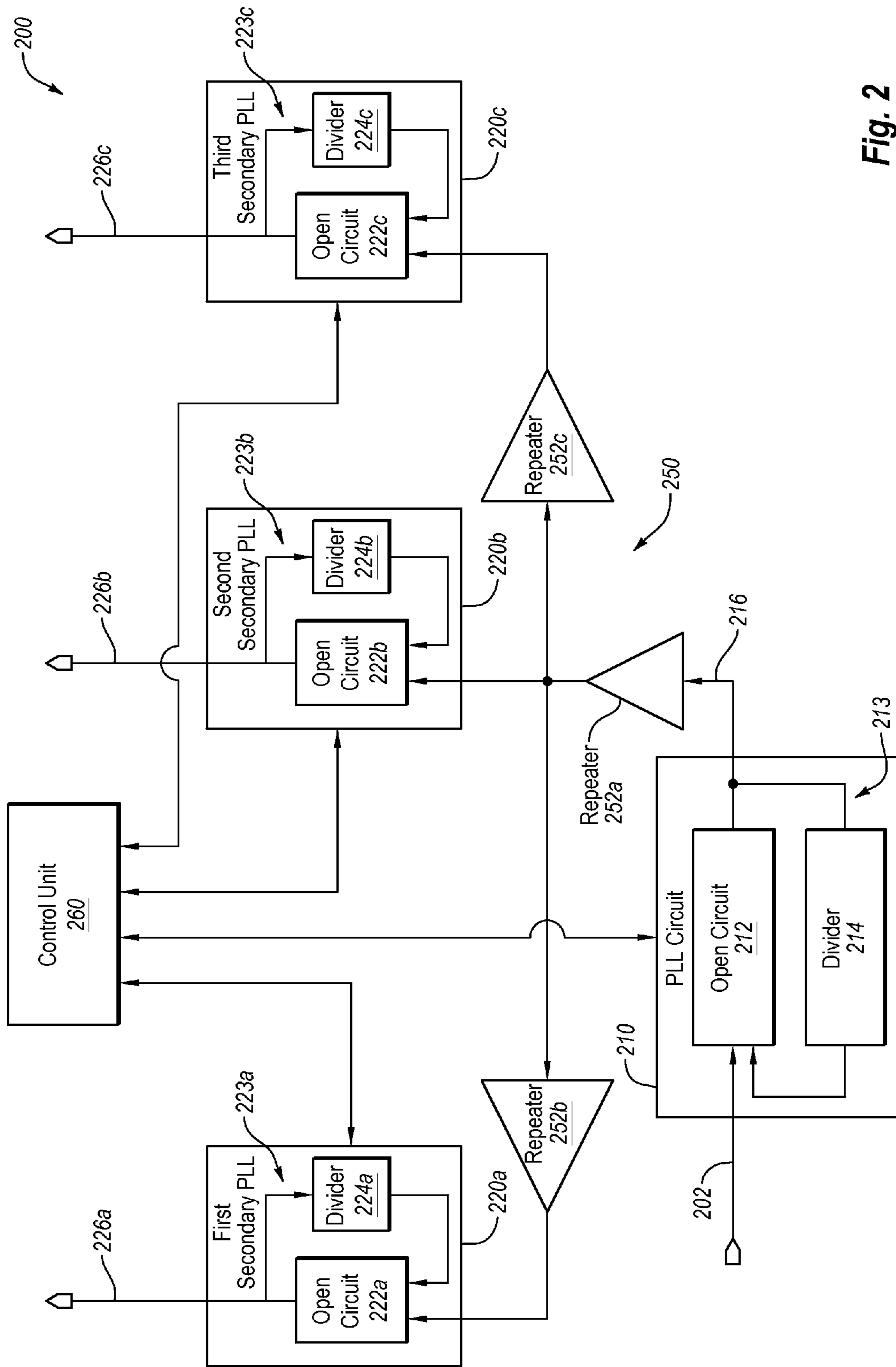


Fig. 2

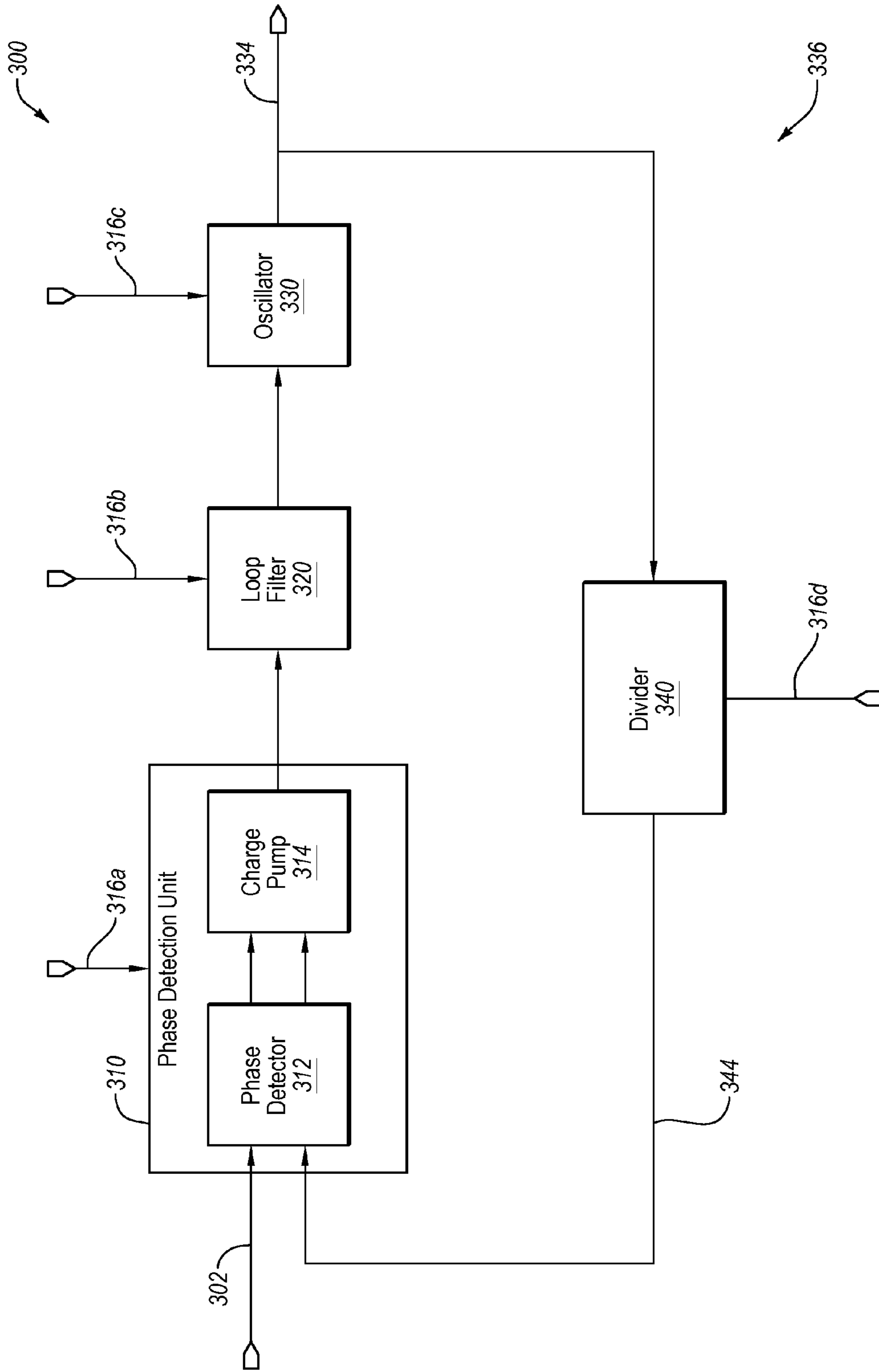


Fig. 3A

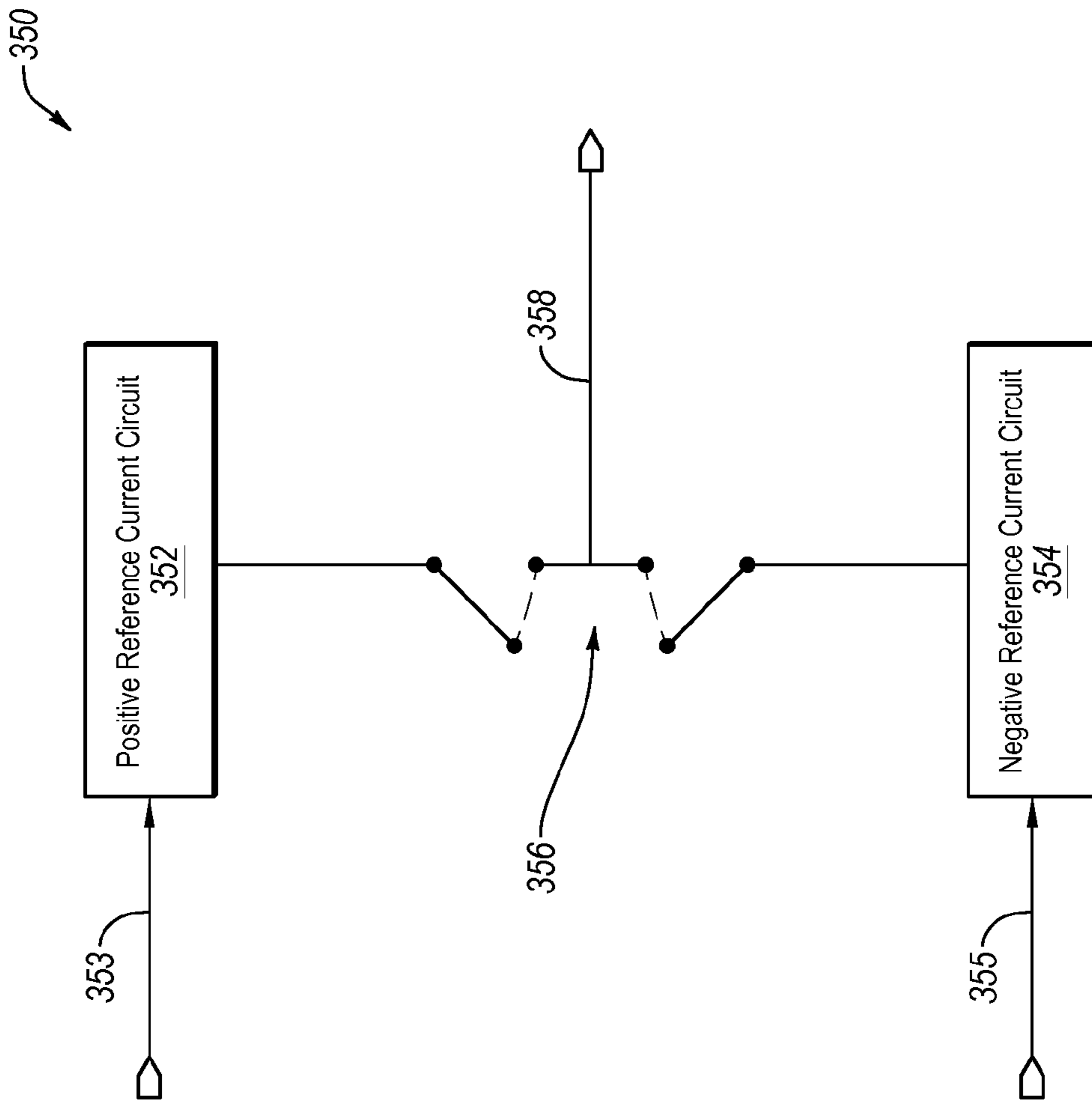


Fig. 3B

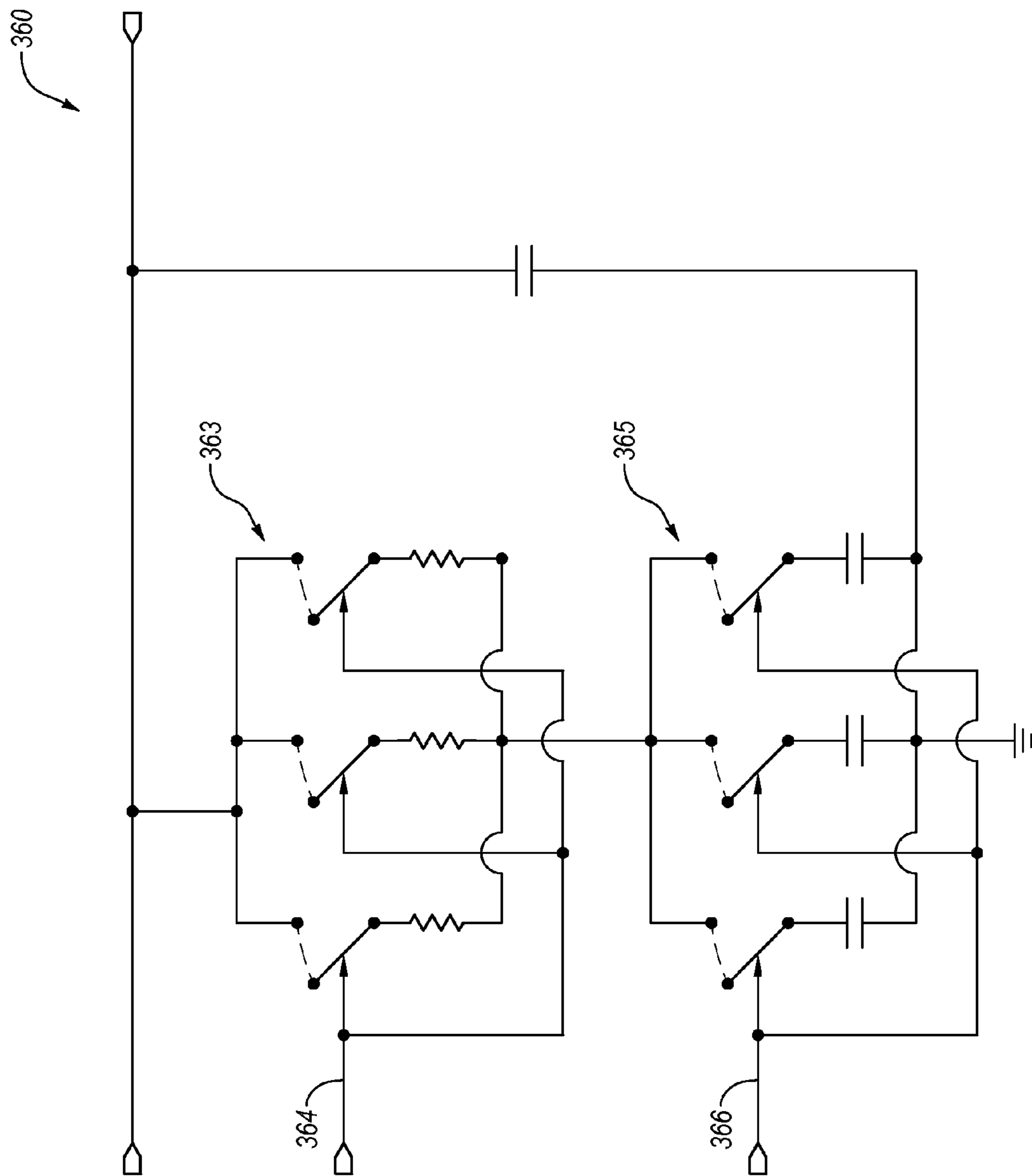


Fig. 3C

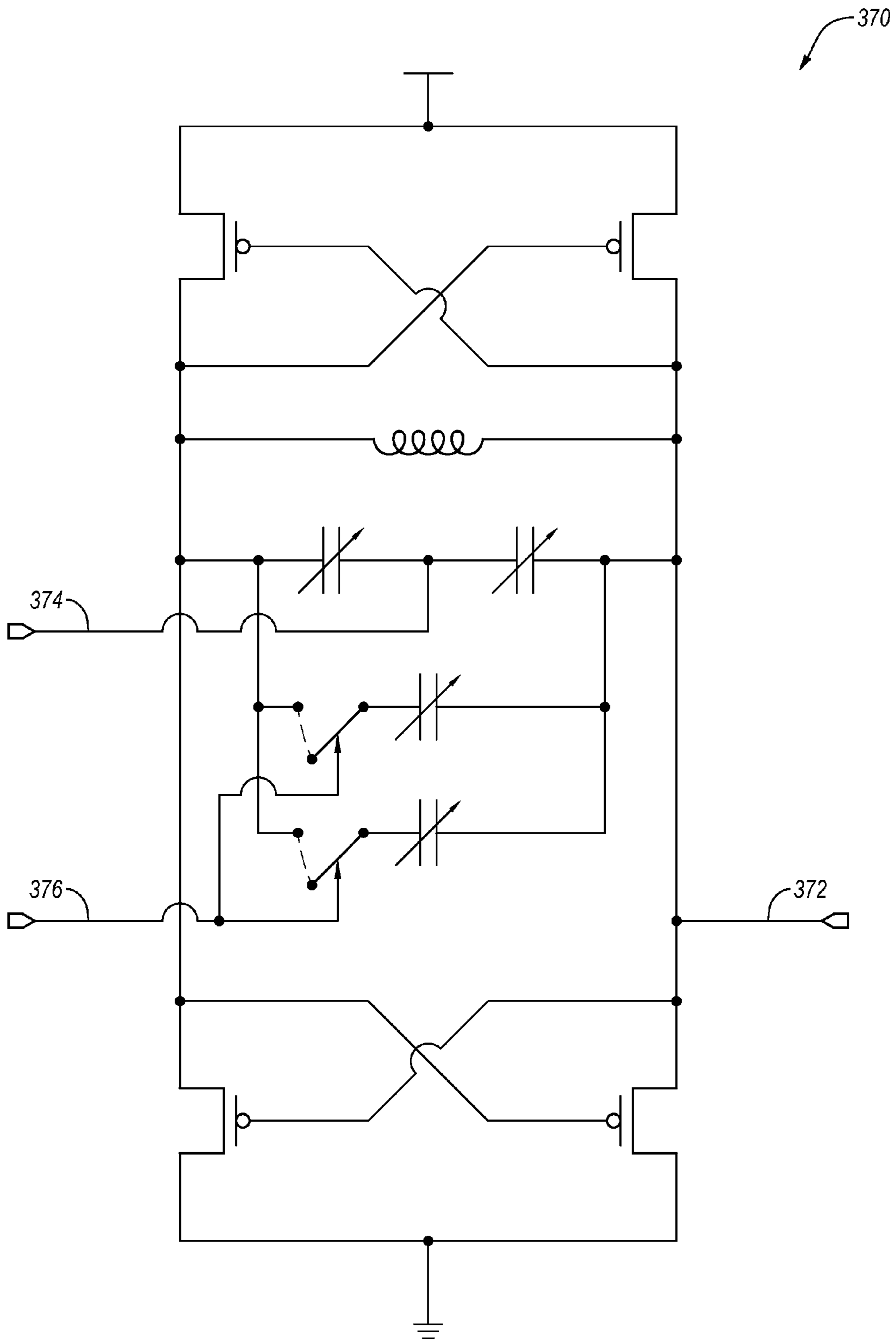


Fig. 3D

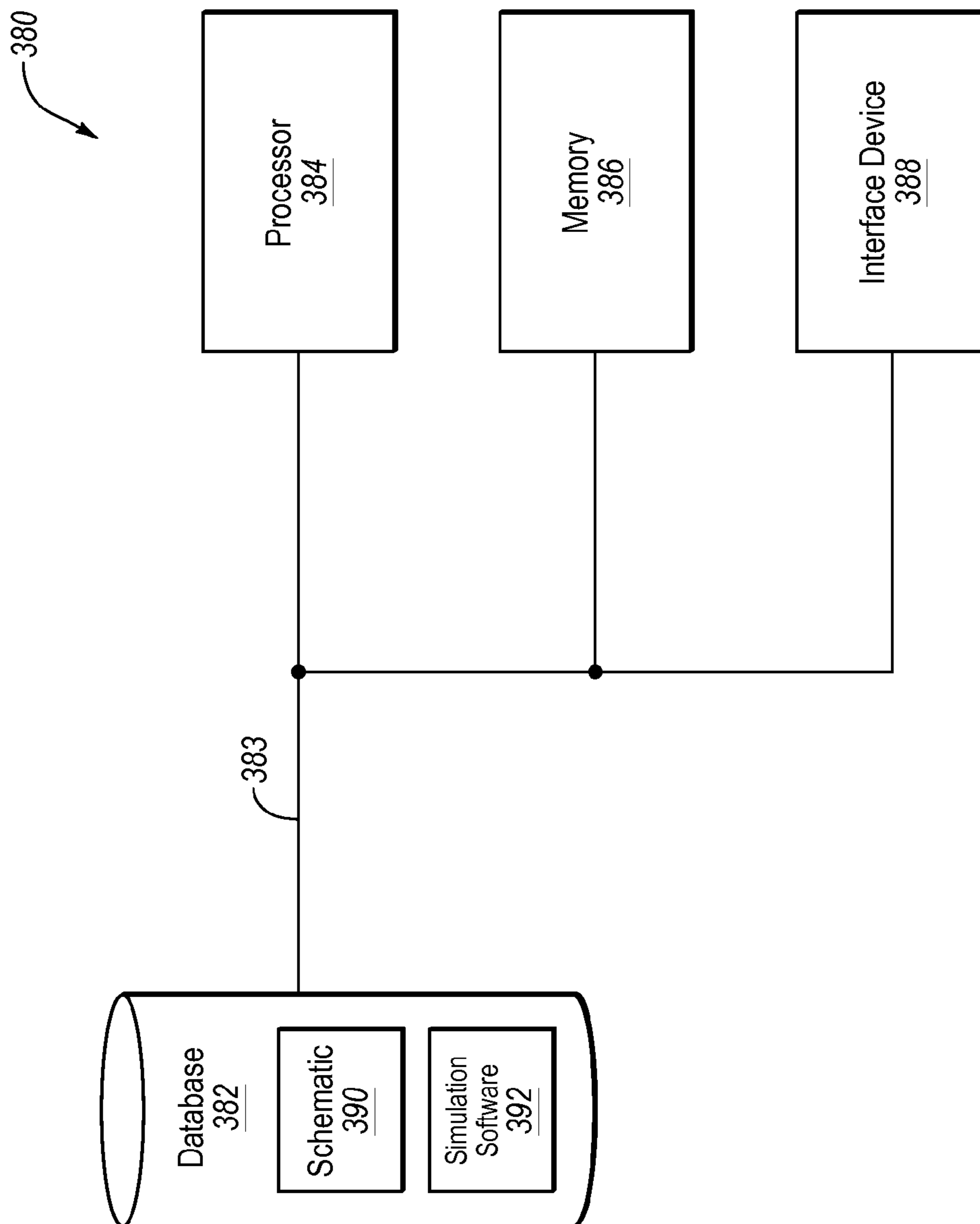


Fig. 3E

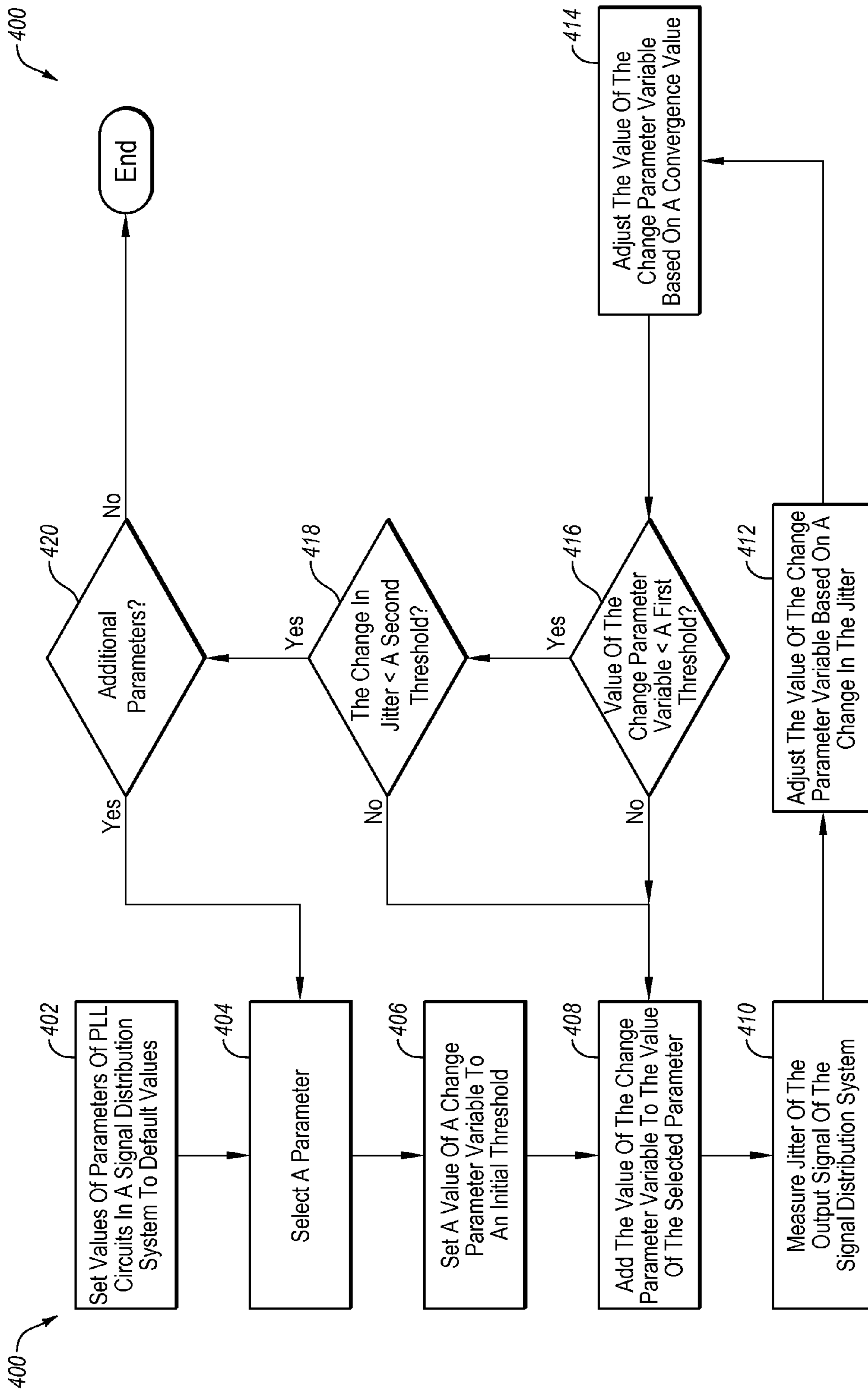
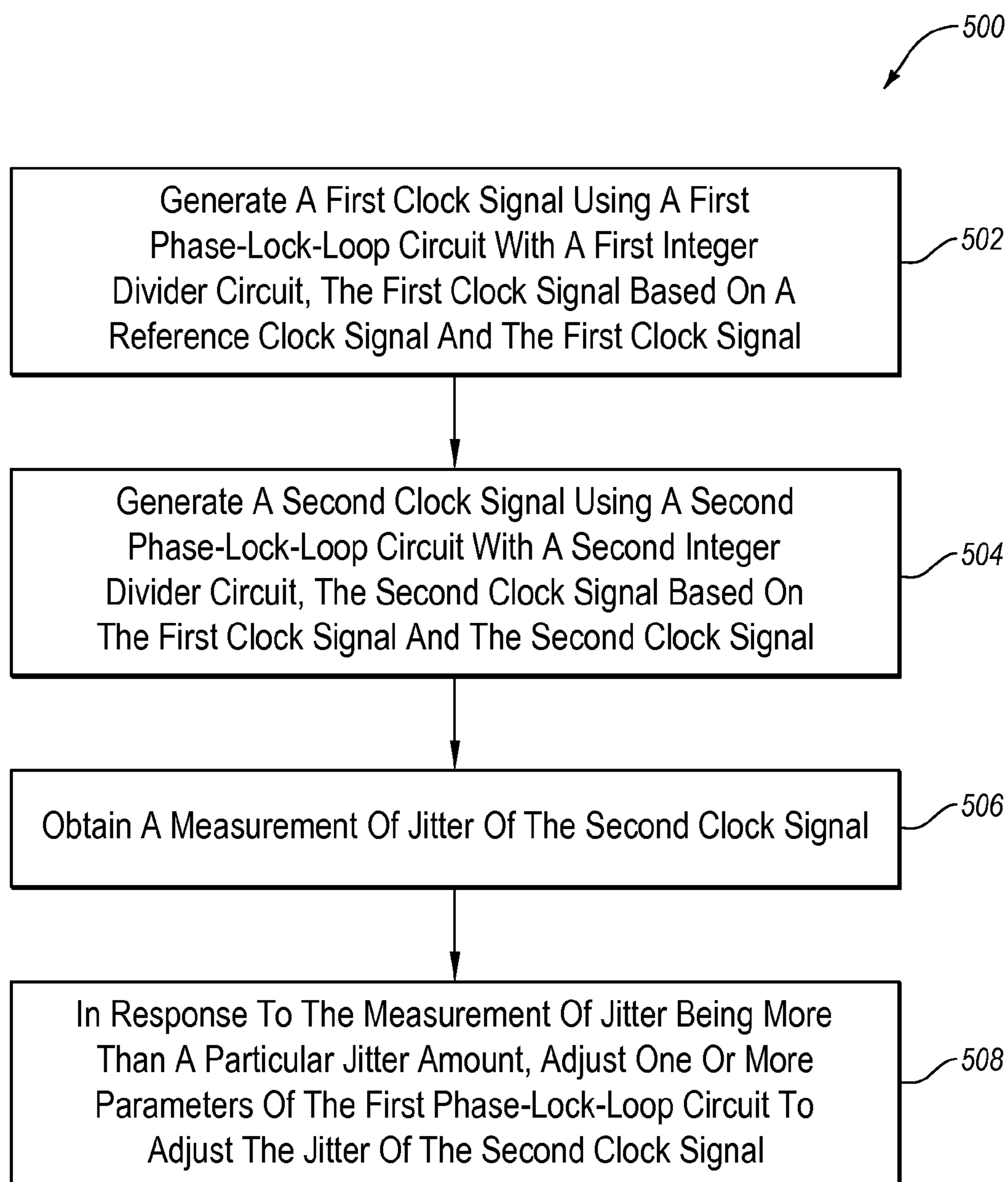


Fig. 4

**Fig. 5**

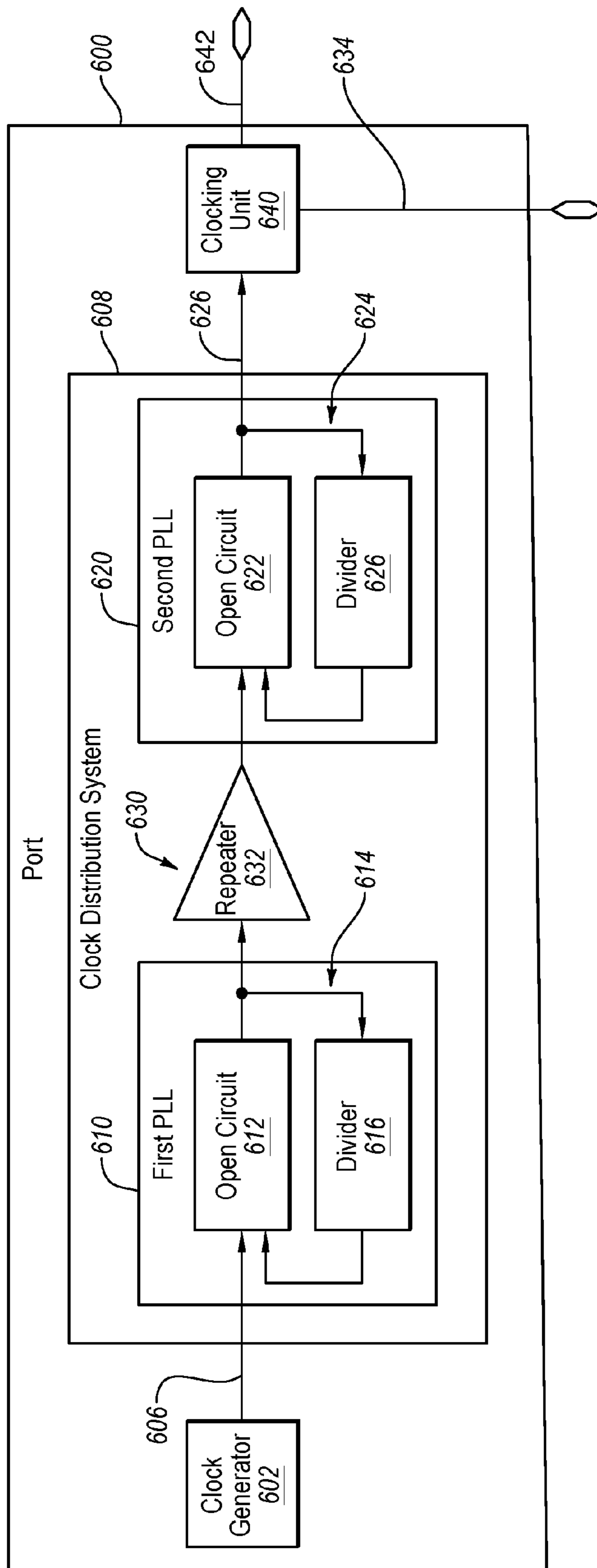


Fig. 6

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CLOCK MULTIPLICATION AND DISTRIBUTION

FIELD

The embodiments discussed herein are related to clock multiplication and distribution.

BACKGROUND

Many devices use high-speed input/output (I/O) ports to transmit information to or receive information from other devices. In some circumstances, the high-speed I/O ports may be grouped together, which each high-speed I/O port using a single lane of the group of high-speed I/O ports. Each of the high-speed I/O ports may be provided with a high-speed clock to clock the data being transmitted to or received from the other devices. These high-speed I/O ports may operate at much higher speeds than the processing speeds used in the transmitting or receiving devices. As a result, higher speed clocks may be generated for the high-speed I/O ports.

The subject matter claimed herein is not limited to embodiments that solve any disadvantages or that operate only in environments such as those described above. Rather, this background is only provided to illustrate one example technology area where some embodiments described herein may be practiced.

SUMMARY

According to an aspect of an embodiment, a clock multiplication and distribution system may include a first phase-lock-loop circuit, a second phase-lock-loop circuit, and a clock distribution network that electrically couples the first phase-lock-loop circuit and the second phase-lock-loop circuit. The first phase-lock-loop circuit may include a first feedback loop that includes a first integer divider circuit and may be configured to generate a first clock using a reference clock. A frequency of the first clock may be greater than a frequency of the reference clock. The second phase-lock-loop circuit may include a second feedback loop that includes a second integer divider circuit and may be configured to generate a second clock using the first clock. A frequency of the second clock may be greater than the frequency of the first clock.

The object and advantages of the embodiments will be realized and achieved at least by the elements, features, and combinations particularly pointed out in the claims.

It is to be understood that both the foregoing general description and the following detailed description are exemplary and explanatory and are not restrictive of the invention, as claimed.

BRIEF DESCRIPTION OF THE DRAWINGS

Example embodiments will be described and explained with additional specificity and detail through the use of the accompanying drawings in which:

FIG. 1 is a block diagram of an example clock multiplication and distribution system;

FIG. 2 is a block diagram of another example clock multiplication and distribution system;

FIG. 3A is a block diagram of an example phase-lock-loop circuit;

FIG. 3B is a block diagram of an example charge pump circuit;

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FIG. 3C is a circuit diagram of an example loop filter circuit;

FIG. 3D is a circuit diagram of an example oscillator circuit;

FIG. 3E is a block diagram of an example system for configuring a clock multiplication and distribution system;

FIG. 4 is a flowchart of an example method of configuring a clock multiplication and distribution system;

FIG. 5 is a flowchart of example method of clock multiplication and distribution; and

FIG. 6 is a block diagram of a high-speed input/output port that includes an example clock multiplication and distribution system

DESCRIPTION OF EMBODIMENTS

According to an aspect of an embodiment, a clock multiplication and distribution system may be configured to multiply a reference clock to an intermediate frequency and distribute the intermediate frequency clock to multiple different locations. At each of the different locations, the intermediate frequency clocks may be multiplied again to a final frequency. For example, the clock multiplication and distribution system may be configured to multiply a reference clock to an intermediate frequency and distribute the intermediate frequency clock to multiple lanes of a high-speed input, output, or input/output (I/O) port. Each lane of the I/O port may independently multiply the intermediate frequency clock to a final frequency clock for use in the corresponding lane.

As another example, a reference clock may be a 500 megahertz (MHz) clock. The reference clock may be multiplied by 7 to become a 3.5 gigahertz (GHz) clock that may be distributed to the multiple different locations. Each of the multiple different locations may multiply the distributed clock clocks by 8 to generate a 28 GHz clock at each of the multiple different locations.

To multiply and distribute the clocks, the clock multiplication and distribution system may include a first phase-locked-loop (PLL) circuit that may be electrically coupled to multiple secondary PLL circuits at the multiple different locations by a clock distribution network that includes one or more repeaters. The first PLL circuit may include a feedback loop with an integer divider circuit and may be configured to generate a first clock using the reference clock. The first clock may be distributed to each of the secondary PLL circuits.

Each of the multiple secondary PLL circuits may also include a feedback loop with an integer divider circuit and may each be configured to generate a second clock using the received first clock. Frequencies of the second clocks may be greater than the frequency of the first clock.

Embodiments of the present disclosure will be explained with reference to the accompanying drawings.

FIG. 1 is a block diagram of an example clock multiplication and distribution system (referred to hereinafter as “the system 100”), arranged in accordance with at least one embodiment described herein. The system 100 includes a first PLL circuit 110, a secondary PLL circuit 120, and a clock distribution network 130 (referred to hereinafter as “the network 130”) that includes a clock repeater 132 that electrically couples the first PLL circuit 110 and the secondary PLL circuit 120.

The first PLL circuit 110 may include an open circuit portion 112 (referred to hereinafter as “the portion 112”) and a feedback loop 114. The feedback loop 114 may include an integer divider circuit 116 (referred to hereinafter as “the divider 116”). The first PLL circuit 110 may be configured to

generate a first clock **118** based on the reference clock **102**. The first clock **118** may be provided to the divider **116** and to the network **130**.

The divider **116** may be configured to generate a feedback clock **119** using the first clock **118** and to provide the feedback clock **119** to the portion **112**. The divider **116** may include an integer divider that divides a frequency of the first clock **118** by an integer divisor greater than 1 to generate the feedback clock **119**. For example, the first clock **118** may include a 4 GHz clock and the divider **116** may be set with an integer divider of 8. In these and other embodiments, the feedback clock **119** may be a 0.5 GHz clock as a result of dividing the 4 GHz first clock **118** by 8.

The portion **112** may compare a phase of the feedback clock **119** and a phase of the reference clock **102** to generate a phase difference. Based on the phase difference, the portion **112** may adjust a frequency/phase of the first clock **118** to drive the phase of the feedback clock **119** to approximate the phase of the reference clock **102**. Because phase is the integral of frequency, the first PLL circuit **110** may operate to drive the frequency of the first clock **118** to an integer multiple or integer multiplication factor of the reference clock **102**, where the integer multiple or multiplication factor is the divisor in the divider **116**. For example, if the reference clock **102** is a 1 GHz clock and the divisor is 7, the first PLL circuit **110** in a locked state may generate a first clock **118** with a frequency of 7 GHz.

The network **130** may include the clock repeater **132** and one or more traces that are configured to provide the first clock **118** to the secondary PLL circuit **120**. In some embodiments, the network **130** may not include the clock repeater **132**. In these and other embodiments, a distance that the first clock **118** may traverse between the first and secondary PLL circuits **110** and **120** may be such that a time delay and/or attenuation of the first clock **118** in the network **130** are acceptable for the system **100**. When the distance between the first and secondary PLL circuits **110** and **120** causes clock delays and/or attenuation of the first clock **118** that may be unacceptable, the network **130** may include the clock repeater **132**. The clock repeater **132** may operate to reduce a time delay and/or attenuation of the first clock **118** while the first clock **118** is transmitted from the first PLL circuit **110** to the secondary PLL circuit **120**.

The clock repeater **132** may include a complementary metal-oxide-semiconductor (CMOS) source-coupled-logic repeater, otherwise known as a current-mode logic (CML) repeater. Alternately or additionally, the clock repeater may include a CMOS inverter repeater.

The secondary PLL circuit **120** may include an open circuit portion **122** (referred to hereinafter as “the portion **122**”) and a feedback loop **124**. The feedback loop **124** may include an integer divider circuit **126** (referred to hereinafter as “the divider **126**”). The secondary PLL circuit **120** may be configured to generate a second clock **128** based on the first clock **118**. The second clock **128** may be provided to the divider **126** and output to another circuit or system, such as a transceiver port in a lane of a high-speed I/O system.

The divider **126** may be configured to generate a feedback clock **129** using the second clock **128** and to provide the feedback clock **129** to the portion **122**. The divider **126** may include an integer divider that divides a frequency of the first clock **118** by an integer divisor greater than 1 to generate the feedback clock **129**.

The portion **122** may compare a phase of the feedback clock **129** and a phase of the first clock **118** to generate a phase difference. Based on the phase difference, the portion **122** may adjust a frequency/phase of the second clock **128** to drive

the phase of the feedback clock **129** to approximate the phase of the first clock **118**. The secondary PLL circuit **120** may thus operate to drive the frequency of the second clock **128** to an integer multiple or integer multiplication factor of the first clock **118**, where the integer multiple or multiplication factor is the divisor in the divider **126**.

The second clock **128** distributed by the system **100** may have less jitter than other clocks distributed by previous clock distribution systems. Alternately or additionally, the system **100** may distribute the second clock **128** with an equal amount of jitter or less jitter than previous clock distribution systems while consuming less power than the previous clock distribution systems. Alternately or additionally, the system **100** may be more easily tuned to reduce jitter of a distributed clock than previous clock distribution systems.

For example, previous clock distribution systems may generate a high frequency clock at a particular operating frequency from a reference clock and may distribute the high frequency clock through a clock distribution network to a different location. These distribution systems may consume a large amount of power and area to distribute the high frequency clock and may utilize a separate conditioned power supply. Furthermore, distributing a high frequency clock may result in distortion of the duty cycle of the high frequency clock. Other previous clock distribution systems may distribute a reference clock to multiple locations and at each of the multiple locations multiply the reference clock to generate the high frequency clocks. In both of these previous clock distribution systems, multiplying a reference clock with a large multiplication factor, e.g., a multiplication factor greater than 15, 20, or 25, may result in increased jitter of the high frequency clock. Furthermore, both of these previous clock distribution systems employ a single unit, such as a PLL, that multiplies the reference clock. As a result, there is limited ability to tune parameters of the unit to adjust the jitter of the high frequency clock in the previous clock distribution systems.

The system **100** illustrated in FIG. 1 may employ the first PLL circuit **110** to multiply the reference clock **102** to generate the first clock **118**. The first clock **118** may be distributed to the secondary PLL circuit **120** that may be employed to multiply the first clock **118** to generate the second clock **128**. As a result, a high frequency clock, e.g., the second clock **128**, may be provided to a location with reduced jitter, power usage, duty cycle distortion, and/or other distortions of the high frequency clock. In particular, the high frequency clock may be provided to a location with reduced jitter, power usage, duty cycle distortion, and/or other distortions when the location is sufficiently far from a reference clock from which the high frequency clock is derived such that a clock repeater is employed to reduce degradation and delay of the clock. In these and other embodiments, a high frequency clock may be a clock with a frequency of greater than approximately 5, 10, 15, 20, or some other frequency GHz.

Because both the first PLL circuit **110** and the secondary PLL circuit **120** multiply clocks to generate the second clock **128**, the multiplication factors, e.g., the divisors, in the first PLL circuit **110** and the secondary PLL circuit **120** may be smaller than the individual multiplication factors in other systems. Using smaller multiplication factors to multiply clocks to generate the second clock **128** may reduce the jitter of the second clock **128**.

Furthermore, because both of the first PLL circuit **110** and the secondary PLL circuit **120** multiply clocks to generate the second clock **128**, the network **130** may carry a clock with a frequency that is less than a frequency of a clock distributed in previous clock distribution systems. The reduced frequency

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of the first clock **118** carried by the network **130** may reduce the power consumption of the network **130** and/or the footprint of the network **130** because inductive peaking or other bandwidth broadening techniques may not be applied to the network **130** to distribute the first clock **118** to the secondary PLL circuit **120**.

In some embodiments, the multiplication factor, e.g., the divisor, of the first PLL circuit **110** may be greater than the multiplication factor of the secondary PLL circuit **120**. As a result, the multiplication factor of the secondary PLL circuit **120** may be reduced as compared to other distribution system or other configurations of the system **100**. Reducing the multiplication factor of the secondary PLL circuit **120** may result in less jitter of the second clock **128**.

Furthermore, in some embodiments, a bandwidth of the secondary PLL circuit **120** may be reduced as compared to a bandwidth of the first PLL circuit **110**. By reducing the bandwidth of the secondary PLL circuit **120**, jitter of the second clock **128** contributed by the first clock **118** may be filtered and reduced. Because the jitter of the first clock **118** may be filtered by the secondary PLL circuit **120**, jitter caused by the network **130** may have less effect on the jitter of the second clock **128**. Jitter caused by the network **130** having less effect on the second clock **128** may reduce the design complexity of the network **130**.

Additionally, the system **100** including both the first and secondary PLL circuits **110** and **120** may increase the ability of the system **100** to tune conditions of the system **100** to decrease the jitter of the second clock **128**. In previous clock distribution systems with a single unit that multiplies a clock, conditions, such as a bandwidth and damping factor, of the unit may be tuned to adjust the jitter of a clock. In the system **100**, however, the conditions of each of the first and secondary PLL circuits **110** and **120** may be tuned individually to decrease the jitter. Increasing the number of conditions that may be tuned may provide the system **100** with better opportunities to adjust the system **100** to reduce the jitter of the second clock **128**.

Modifications, additions, or omissions may be made to the system **100** without departing from the scope of the present disclosure. For example, the network **130** may not include the repeater **132** or may include multiple repeaters. Alternately or additionally, the system **100** may include one or more other passive or active components or circuits than those illustrated in the system **100**. For example, the system **100** may be expandable to include multiple secondary PLL circuits **120** in different locations that each receive the first clock **118** from the first PLL circuit **110** through the network **130**.

FIG. **2** is a block diagram of another example clock multiplication and distribution system **200** (referred to herein as “the system **200**”), arranged in accordance with at least one embodiment described herein. The system **200** includes a first PLL circuit **210**; a clock distribution network **250**; first, second, and third secondary PLL circuits **220a**, **220b**, and **220c** (referred to herein as “the secondary PLL circuit(s) **220**”); and a control unit **260**.

The first PLL circuit **210** may include an open circuit portion **212** (referred to hereinafter as “the portion **212**”) and a feedback loop **213**. The feedback loop **213** may include an integer divider circuit **214** (referred to hereinafter as “the divider **214**”). The first PLL circuit **210** may be configured to generate a first clock **216** based on the reference clock **202**. The frequency of the first clock **216** may be based on the frequency of the reference clock **202** and the divisor of the divider **214**. The first PLL circuit **210** may operate in an analogous manner as the first PLL circuit **110** of FIG. **1**.

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The first secondary PLL circuit **220a** may include a first open circuit portion **222a** (referred to hereinafter as “the first portion **222a**”) and a first feedback loop **223a**. The first feedback loop **223a** may include a first integer divider circuit **224a** (referred to hereinafter as “the first divider **224a**”). The first secondary PLL circuit **220a** may be configured to generate a first secondary clock **226a** based on the first clock **216**. The frequency of the first secondary clock **226a** may be based on the frequency of the first clock **216** and the divisor of the first divider **224a**.

The second secondary PLL circuit **220b** may include a second open circuit portion **222b** (referred to hereinafter as “the second portion **222b**”) and a second feedback loop **223b**. The second feedback loop **223b** may include a second integer divider circuit **224b** (referred to hereinafter as “the second divider **224b**”). The second secondary PLL circuit **220b** may be configured to generate a second secondary clock **226b** based on the first clock **216**. The frequency of the second secondary clock **226b** may be based on the frequency of the first clock **216** and the divisor of the second divider **224b**.

The third secondary PLL circuit **220c** may include a third open circuit portion **222c** (referred to hereinafter as “the third portion **222c**”) and a third feedback loop **223c**. The third feedback loop **223c** may include a third integer divider circuit **224c** (referred to hereinafter as “the third divider **224c**”). The third secondary PLL circuit **220c** may be configured to generate a third secondary clock **226c** based on the first clock **216**. The frequency of the third secondary clock **226c** may be based on the frequency of the first clock **216** and the divisor of the third divider **224c**. Each of the secondary PLL circuits **220** may operate in an analogous manner as the secondary PLL circuit **120** of the FIG. **1**.

The first portion **222a**, the second portion **222b**, and the third portion **222c** may be referred to hereinafter as “the portion(s) **222**.” The first feedback loop **223a**, the second feedback loop **223b**, and the third feedback loop **223c** may be referred to hereinafter as the “feedback loop(s) **223**.” The first divider **224a**, the second divider **224b**, and the third divider **224c** may be referred to herein as “the divider(s) **224**.” The first secondary clock **226a**, the second secondary clock **226b**, and the third secondary clock **226c** may be referred to herein as “the secondary clock(s) **226**.”

In some embodiments, the integer divisors of the dividers **224** of the secondary PLL circuits **220** may be the same or different. As a result, a frequency of each of the secondary clocks **226** may be approximately the same or different.

The clock distribution network **250** may include first, second, and third clock repeaters **252a**, **252b**, and **252c** (referred to hereinafter as “the clock repeater(s) **252**”) and one or more traces that are configured to provide the first clock **216** to the secondary PLL circuits **220**. Each of the clock repeaters **252** may include an emitter-coupled-logic repeater, a CMOS repeater, or the clock repeaters **252** may include some combination thereof.

The first clock repeater **252a** may provide the first clock **216** to the second secondary PLL circuit **220b** and to the second and third clock repeaters **252b** and **252c**. The second clock repeater **252b** may provide the first clock **216** to the first secondary PLL circuit **220a**. The third clock repeater **252c** may provide the first clock **216** to the third secondary PLL circuit **220c**.

The control unit **260** may be configured to monitor the jitter of the secondary clocks **226**. Based on the jitter on the secondary clocks **226**, the control unit **260** may adjust conditions of the secondary PLL circuits **220** and the first PLL circuit **210** to adjust the jitter of the secondary clocks **226**.

To monitor the jitter of the secondary clocks **226**, the control unit **260** may monitor the secondary clocks **226**. For example, the control unit **260** may obtain an indication of the jitter of the secondary clocks **226** from circuits configured to monitor the jitter of the secondary clocks **226**. Alternately or additionally, the control unit **260** may obtain an indication of the jitter of the secondary clocks **226** from data signals that are clocked with the secondary clocks **226**. In these and other embodiments, the jitter of the secondary clocks **226** may be an indication of an amount that the clock edges of the secondary clocks **226** move in time from a set time interval for the clock edges based on a frequency of the secondary clocks **226**.

In response to the jitter of one or more of the secondary clocks **226** being above a threshold, the control unit **260** may adjust conditions of one or more of the secondary PLL circuits **220** and/or the first PLL circuit **210**. The threshold may be based on the characteristics of the hardware using the secondary clocks **226**. For example, some hardware may tolerate jitter that is less than 5, 10, 15, or some other percent of a cycle of the secondary clocks **226**. In these and other embodiments, the threshold may be equal to the jitter tolerance of the hardware using the secondary clocks **226**. Alternately or additionally, the threshold may be based on the jitter tolerance of the hardware using the secondary clocks **226**. For example, when the jitter tolerance is 10 percent of a cycle of the secondary clocks **226** and the jitter reaches 7 percent of the cycle, the control unit **260** may adjust conditions of one or more of the secondary PLL circuits **220** and/or the first PLL circuit **210**.

In some embodiments, the conditions of the secondary PLL circuits **220** and the first PLL circuit **210** that may be adjusted by the control unit **260** may include the bandwidth and the damping factor of the secondary PLL circuits **220** and the first PLL circuit **210**. In these and other embodiments, the control unit **260** may adjust these conditions by adjusting one or more parameters of the secondary PLL circuits **220** and the first PLL circuit **210**. The parameters may include an oscillator gain, a charge pump gain, loop filter parameters, which may be based on a resistance and/or a capacitance of a loop filter, and divisors of the dividers **224** and the divider **214**, among others.

The control unit **260** may adjust the conditions of each of the secondary PLL circuits **220** and the first PLL circuit **210** individually or collectively. Alternately or additionally, the control unit **260** may adjust the conditions of each of the secondary PLL circuits **220** and the first PLL circuit **210** to achieve jitter that is above a threshold for each of the secondary clocks **226**. Alternately or additionally, the control unit **260** may adjust the conditions of each of the secondary PLL circuits **220** and the first PLL circuit **210** to achieve jitter that may be optimized for one or more of the secondary clocks **226** and not others of the secondary clocks **226**.

In some embodiments, when the jitter of one of the secondary clocks **226** is above the threshold, the control unit **260** may adjust the conditions of each secondary PLL circuit **220** and the first PLL circuit **210**. Alternately or additionally, the control unit **260** may adjust the conditions for the secondary PLL circuit **220** that generates the one of the secondary clocks **226** that is above the threshold.

Alternately or additionally, the control unit **260** may first adjust the conditions for the secondary PLL circuit **220** that generates the one of the secondary clocks **226** with jitter above the threshold. If the conditions of the secondary PLL circuit **220** may not be adjusted to reduce the jitter below the threshold, the control unit **260** may further adjust the condi-

tions of the first PLL circuit **210** and the secondary PLL circuit **220** until the jitter of the one of the secondary clocks **226** is below the threshold.

Adjusting the conditions of the first PLL circuit **210** may affect the jitter of other of the secondary clocks **226**. Thus, the control unit **260** may monitor the effect of the adjustment of the first PLL circuit **210** on the jitter of the other secondary clocks **226**. When the jitter of the other secondary clocks **226** may be affected such that their jitter may be increased above the threshold, the control unit **260** may adjust the conditions of the secondary PLL circuits **220** that generate the other secondary clocks **226** with jitter above the threshold individually or may adjust the conditions of each of the secondary PLL circuits **220** and the first PLL circuit **210** to achieve jitter that may be below the threshold for each of the secondary clocks **226**.

By adjusting the conditions of the secondary PLL circuit **220** and the first PLL circuit **210**, the control unit **260** may adapt the system **200** for changing conditions. For example, a change in temperature, voltage, electromagnetic disturbance, noise, or some other variable in the system **200** may change. Changes in the system **200** may affect the jitter of the secondary clocks **226**. The control unit **260** may adjust the conditions of the secondary PLL circuit **220** and the first PLL circuit **210** to help to reduce or account for the change in the jitter of the secondary clocks **226**. In these and other embodiments, the control unit **260** may monitor the secondary clocks **226** in real-time during operation of the system **200** and may adjust the system **200** accordingly. Alternately or additionally, the control unit **260** may operate at power-up or at some other set or variable operation interval of the system **200**. Alternately or additionally, the control unit **260** may function to adjust the conditions of the secondary PLL circuit **220** and the first PLL circuit **210** after fabrication to account for variations in the fabrication of the system **200**. In these and other embodiments, the control unit **260** may set the conditions for the secondary PLL circuit **220** and the first PLL circuit **210** after fabrication that may be used during all future operations of the system **200**.

Modifications, additions, or omissions may be made to the system **200** without departing from the scope of the present disclosure. For example, the system **200** may include fewer or more than the three secondary PLL circuits **220**. In these and other embodiments, each of the secondary PLL circuits **220** may receive the first clock **216** from the first PLL circuit **210** and may have their conditions controlled by the control unit **260**.

In some embodiments, the system **200** may not include the control unit **260**. In these and other embodiments, the system **200** may be simulated and analyzed and the conditions of the secondary PLL circuits **220** and the first PLL circuit **210** may be set before fabrication of the system **200**.

FIG. 3A is a block diagram of an example PLL circuit **300** (referred to hereinafter as “circuit **300**”), arranged in accordance with at least one embodiment described herein. The circuit **300** may be an example of the first and/or secondary PLL circuits **110** and **120** of FIG. 1, the first PLL circuit **210** of FIG. 2, and/or any of the secondary PLL circuits **220** of FIG. 2. The circuit **300** includes a phase detection unit **310**, a loop filter circuit **320**, an oscillator circuit **330**, and a divider circuit **340**.

The phase detection unit **310** may include a phase detector circuit **312** and a charge pump circuit **314**. The phase detector circuit **312** may output a voltage that may be proportional to a phase error between a reference clock **302** and a divided output clock **344** from the divider circuit **340**. The voltage may be provided to the charge pump circuit **314** that converts the voltage to a current that may be an average of the phase error between the reference clock **302** and the divided output

clock 344. The charge pump circuit 314 provides the current to the loop filter circuit 320. The loop filter circuit 320 filters the current and converts the current to a voltage that may be provided to the oscillator circuit 330. The oscillator circuit 330 generates the output clock 334 with a frequency proportional to the voltage provided by the loop filter circuit 320. The output clock 334 may also be provided to the divider circuit 340. The divider circuit 340 divides the output clock 334, e.g., reduces the frequency of the output clock 334 proportional to a divisor of the divider circuit 340, and provides the divided output clock 344 to the phase detector circuit 312.

FIG. 3A further illustrates controls signals 316 that are configured to adjust parameters of the phase detection unit 310, the loop filter circuit 320, the oscillator circuit 330, and the divider circuit 340. The control signals 316 may be generated by a control unit, such as the control unit 260 of FIG. 2. The control signals 316 may include a first control signal 316a that may adjust parameters of the phase detection unit 310. The adjustable parameters of the phase detection unit 310 may include a gain of the phase detection unit 310. In particular, a gain of the charge pump circuit 314 may be adjusted by adjusting a reference current used by the charge pump circuit 314. The phase detection unit 310 is illustrated as an analog device. In some embodiments, the phase detection unit 310 may be digital. In these and other embodiments, a gain of the output of the phase detection unit 310 may be adjusted by the first control signal 316a.

The control signals 316 may also include a second control signal 316b that may adjust the parameters of the loop filter circuit 320. The adjustable parameter of the loop filter circuit 320 may include one or more capacitances in the loop filter circuit 320, a resistance in the loop filter circuit 320, or some other passive component value in the loop filter circuit 320. In some embodiments, the loop filter circuit 320 may be digital. In these and other embodiments, a gain of the loop filter circuit 320 or some other variable of the loop filter circuit 320 may be adjusted by the second control signal 316b.

The control signals 316 may also include a third control signal 316c that may adjust the parameters of the oscillator circuit 330. The adjustable parameters of the oscillator circuit 330 may include a gain of the oscillator circuit 330. The gain of the oscillator circuit 330 may indicate an amount that a change in the voltage received from the loop filter circuit 320 changes the frequency of the output clock 334.

The control signals 316 may also include a fourth control signal 316d that may adjust the parameters of the divider circuit 340. The adjustable parameters of the divider circuit 340 may include a value of the divisor of the divider circuit 340.

Adjusting the parameters of the phase detection unit 310, the loop filter circuit 320, the oscillator circuit 330, and the divider circuit 340 may adjust conditions of the circuit 300. In particular, adjusting the parameters of the phase detection unit 310, the loop filter circuit 320, the oscillator circuit 330, and the divider circuit 340 may adjust a bandwidth and a damping factor of the circuit 300.

The bandwidth of the circuit 300 may be proportional to the natural frequency, given by the following equation:

$$\omega = \sqrt{\frac{K_{PD} \times K_{VCO}}{N \times C_0}}$$

where ω is the natural frequency, K_{PD} is the gain of the phase detection unit 310, K_{VCO} is the gain of the oscillator

circuit 330, N is the divisor of the divider circuit 340, and C_0 is the value of a capacitor in the loop filter circuit 320. Thus, adjusting the natural frequency of the circuit 300 may adjust the bandwidth of the circuit 300.

The damping factor of the circuit 300 may be given by the following equation:

$$\zeta = \frac{r_0}{2} \sqrt{\frac{K_{PD} \times K_{VCO} \times C_0}{N}}$$

where ξ is the damping factor and r_0 is the value of a resistor in the loop filter circuit 320.

As may be determined from the above equations, the damping factor and the bandwidth of the circuit 300 may be affected by adjusting the parameters of any one of the phase detection unit 310, the loop filter circuit 320, the oscillator circuit 330, and the divider circuit 340. Furthermore, numerous of the parameters of the phase detection unit 310, the loop filter circuit 320, the oscillator circuit 330, and the divider circuit 340 may adjust the damping factor and the bandwidth. Thus, in some embodiments, both the bandwidth and the damping factor may be adjusted when a single parameter is adjusted.

In some embodiments, the jitter of the output clock 334 may be caused by jitter of the reference clock 302 and by jitter generated by the circuit 300. Adjusting the bandwidth of the circuit 300 may adjust an amount of jitter of the output clock 334 that results from the jitter of the reference clock 302 or the jitter generated by the circuit 300. For example, reducing the bandwidth may suppress the jitter of the reference clock 302 that may be transferred to the output clock 334 and may increase the jitter generated by the circuit 300 that may be transferred to the output clock 334. Conversely, increasing the bandwidth may increase the jitter of the reference clock 302 that may be transferred to the output clock 334 and may suppress the jitter generated by the circuit 300 that may be transferred to the output clock 334. As a result, the bandwidth of the circuit 300 may be adjusted to suppress the type of jitter that contributes the most to the jitter of the output clock 334.

For example, in the system 100 of FIG. 1, the divisor in the first PLL circuit 110 may be larger than the divisor in the secondary PLL circuit 120. As a result, the jitter generated by the first PLL circuit 110 may be larger than the jitter generated by the secondary PLL circuit 120. Furthermore, the jitter of the first clock 118 when received by the secondary PLL circuit 120 after the first clock 118 may be transferred by the network 130 may be greater than the jitter of the reference clock 102. As a result, the secondary PLL circuit 120 may have a bandwidth that may be lower than the bandwidth of the first PLL circuit 110 to allow the secondary PLL circuit 120 to suppress the jitter from the first clock 118 and to allow the first PLL circuit 110 to suppress the jitter generated by the first PLL circuit 110.

Modifications, additions, or omissions may be made to the circuit 300 without departing from the scope of the present disclosure. For example, the circuit 300 may be an analog PLL circuit, a digital PLL circuit, and/or an all-digital PLL circuit.

FIG. 3B is a block diagram of an example charge pump circuit 350 that may be an example of the charge pump circuit 314 of FIG. 3A, arranged in accordance with at least one embodiment described herein. A parameter (or multiple parameters) of the charge pump circuit 350 may be adjusted. The parameter may include a reference current of the charge pump circuit 350,

As illustrated, the charge pump circuit **350** includes a positive reference current circuit **352** and a negative reference current circuit **354** that are both used to generate an output current clock **358** based on the behavior of switches **356**. A first adjust signal **353** may adjust a positive reference current output by the positive reference current circuit **352**. A second adjust signal **355** may adjust a negative reference current output by the negative reference current circuit **354**. Modifications, additions, or omissions may be made to the charge pump circuit **350** without departing from the scope of the present disclosure.

FIG. **3C** is a circuit diagram of an example loop filter circuit **360** that may be an example of the loop filter circuit **320** of FIG. **3A**, arranged in accordance with at least one embodiment described herein. A parameter (or multiple parameters) of the loop filter circuit **360** may be adjusted. The parameter may include a resistance **363** and/or a capacitance **365** of the loop filter circuit **360**. As illustrated, a first control signal **364** may open and or close switches to increase or decrease the resistance **363** of the loop filter circuit **360**. A second control signal **366** may open and/or close other switches to increase or decrease the capacitance **365** of the loop filter circuit **360**.

Modifications, additions, or omissions may be made to the loop filter circuit **360** without departing from the scope of the present disclosure. For example, the resistance **363** may include a variable resistor that may be controlled by the first control signal **364**. Alternately or additionally, the capacitance **365** may include a varactor that may be controlled by the second control signal **366**.

FIG. **3D** is a circuit diagram of an example oscillator circuit **370** that may be an example of the oscillator circuit **330** of FIG. **3A**, arranged in accordance with at least one embodiment described herein. A parameter (or multiple parameters) of the oscillator circuit **370** may be adjusted. The parameter may include a gain of the oscillator circuit **370**. The gain of the oscillator circuit **370** may be adjusted by a first control signal **376** that may adjust an amount of capacitance that may be switched into the oscillator circuit **370**. Adjusting the capacitance of the oscillator circuit **370** may adjust how the oscillator circuit **370** adjusts a frequency of an output clock **372** with respect to a received voltage control signal **374** that tunes an amount of capacitance that may be switched into the oscillator circuit **370**. Modifications, additions, or omissions may be made to the oscillator circuit **370** without departing from the scope of the present disclosure.

FIG. **3E** is a block diagram of an example system **380** for configuring a clock multiplication and distribution system (referred to hereinafter as “the system **380**”), arranged in accordance with at least one embodiment described herein. The system **380** may be configured to adjust parameters of PLL circuits, such as the circuit **300** of FIG. **3A**, in a clock multiplication and distribution system before the clock multiplication and distribution system may be manufactured in hardware. In these and other embodiments, based on a simulation of the clock multiplication and distribution system, the system **380** may be able to select parameters for the PLL circuits in the clock multiplication and distribution system that may result in the clocks output by the clock multiplication and distribution system including jitter less than a threshold.

The system **380** may include a database **382**, a processor **384**, a memory **386**, and an interface device **388**. The database **382**, the processor **384**, the memory **386**, and the interface device **388** may be communicatively coupled by a bus or network **383**.

The processor **384** may include, for example, a microprocessor, a microcontroller, a digital signal processor (“DSP”),

an application-specific integrated circuit (“ASIC”), a Field-Programmable Gate Array (“FPGA”), or any other digital or analog circuitry configured to interpret and/or to execute program instructions and/or to process data. In some embodiments, the processor **384** may interpret and/or execute program instructions and/or process data stored in the associated memory **386**. Although a single processor **384** is illustrated, the system **380** may include multiple processors.

The memory **386** may include any suitable computer-readable media configured to retain program instructions and/or data for a duration of time. By way of example, and not limitation, such computer-readable media may include tangible and/or non-transitory computer-readable storage media, including Random Access Memory (“RAM”), Read-Only Memory (“ROM”), Electrically Erasable Programmable Read-Only Memory (“EEPROM”), Compact Disk Read-Only Memory (“CD-ROM”) or other optical disk storage, magnetic disk storage or other magnetic storage devices, flash memory devices (e.g., solid state memory devices), or any other storage medium which may be used to carry or store desired program code in the form of computer-executable instructions or data structures and which may be accessed by the processor **384**. Combinations of the above may also be included within the scope of computer-readable media. Computer-executable instructions may include, for example, instructions and data that cause a general-purpose computer, special-purpose computer, or special-purpose processing device (e.g., the processor **384**) to perform a certain function or group of functions.

The database **382** may include a schematic representation **390** of a clock multiplication and distribution system and simulation software **392**. The simulation software **392** may include computer instructions, that when executed by a processor, such as the processor **384**, may simulate the schematic representation **390** to estimate jitter of an output clock of the schematic representation **390** of the clock multiplication and distribution system. Various parameters of the schematic representation **390** may be adjusted during the simulation to adjust the jitter of the output clock as described herein. Values of the parameters that result in the jitter being less than a threshold during the simulation of the schematic representation **390** may be noted and used during fabrication of the clock multiplication and distribution system in hardware. In this manner, the parameters of the clock multiplication and distribution system may be adjusted prior to fabrication to achieve jitter less than a threshold.

In these and other embodiments, the computer instructions executed by the processor **384** may be loaded into the memory **386** for execution by the processor **384** and/or data generated, received, or operated on during simulation of the schematic representation **390** herein may be at least temporarily stored in the memory **386**. The interface device **388** may be configured to receive data, such as parameters of the clock multiplication and distribution system, from and/or to send data to other systems, users, and/or other processes over any type of communications network. Modifications, additions, or omissions may be made to the system **380** without departing from the scope of the present disclosure.

FIG. **4** is a flowchart of an example method **400** of configuring a clock multiplication and distribution system, arranged in accordance with at least one embodiment described herein. The method **400** may be implemented, in some embodiments, by a clock multiplication and distribution system, such as the clock multiplication and distribution systems **100**, **200**, or **608** of FIGS. **1**, **2**, and **6**. The method **400** may include adjusting one or more parameters of various PLL circuits in a clock multiplication and distribution system that may be

implemented in hardware to adjust the jitter of an output clock of the clock multiplication and distribution system. The method **400** may be performed by sending information to the PLL circuits over an I²C interface, a IEEE 1149.1 (JTAG) interface, or some other hardware interface that may provide information, such as bits or bytes to the PLL circuits in the clock multiplication and distribution system.

Although illustrated as discrete blocks, various blocks may be divided into additional blocks, combined into fewer blocks, or eliminated, depending on the desired implementation.

The method **400** may begin at block **402**, where values of parameters of PLL circuits in the clock multiplication and distribution system may be set to default values. The PLL circuits may include a first PLL circuit and a secondary PLL circuit. The jitter of an output clock from the secondary PLL circuit of the clock multiplication and distribution system may be measured. In block **404**, a parameter from among the parameters of the PLL circuits may be selected.

In block **406**, a value of a change parameter variable for the selected parameter may be set to an initial threshold. The initial threshold for the change parameter variable may be selected based on a configuration of the PLL circuits, a configuration of the clock multiplication and distribution system, and a default value of the parameters.

In block **408**, a value of the change parameter variable may be added to the value of the selected parameter. In block **410**, the jitter of the output clock from the secondary PLL circuit of the clock multiplication distribution system may again be measured.

In block **412**, the value of the change parameter variable may be adjusted based on a change in the jitter of the output clock. In some embodiments, the value of the change parameter variable for the selected parameter may be equal to the change in the jitter divided by the value of the change parameter variable. The change in the jitter may be calculated based on the jitter measurement made in block **410** and a previous jitter measurement made before the current change to the value of the selected parameter.

In block **414**, the value of the change parameter variable may be adjusted based on a convergence value. For example, the value of the change parameter variable may be multiplied by the convergence value. In these and other embodiments, the convergence value may be between 0 and 1 and may be selected based on previous iterations of the method **400**. In some embodiments, the convergence value may be approximately 0.1.

In block **416**, it may be determined if the value of the change parameter variable is less than a first threshold. The first threshold may be based on the minimum amount for which the value of the selected parameter may be changed. For example, for a capacitance in a loop filter, the first threshold would be based on a smallest adjustment that may be made to the capacitance of the loop filter.

When the value of the change parameter variable is less than the first threshold, the method **400** may proceed to block **418**. When the value of the change parameter variable is not less than the first threshold, the method **400** may proceed to block **408**.

In block **418**, it may be determined if the change in jitter determined in block **414** is less than a second threshold. The second threshold may be based on a configuration of the clock multiplication and distribution system, an amount of acceptable jitter, and/or prior experience. For example, in some embodiments, a change in jitter of less than 0.5%, 1%, 3%, 5%, or 10% of a unit interval or some other amount of time may be selected.

When the change in jitter is less than the second threshold, the method **400** may proceed to block **420**. When the change in jitter is not less than the second threshold, the method **400** may proceed to block **408**.

In block **420**, it may be determined if there are parameters of the PLL circuits in the clock multiplication and distribution system that have not been selected. When one or more of the parameters of the PLL circuits in the clock multiplication and distribution system have not been selected, the method **400** may proceed to block **404**. When there are no additional parameters of the PLL circuits in the clock multiplication and distribution system to be selected, in some embodiments, the method **400** may end.

One skilled in the art will appreciate that, for this and other processes and methods disclosed herein, the functions performed in the processes and methods may be implemented in differing order. Furthermore, the outlined steps and operations are only provided as examples, and some of the steps and operations may be optional, combined into fewer steps and operations, or expanded into additional steps and operations without detracting from the essence of the disclosed embodiments.

For example, the method **400** may continue for additional secondary PLL circuits in the clock multiplication and distribution system. In these and other embodiments, the parameters from the additional secondary PLL circuits may be adjusted individually without readjusting the parameters of the first PLL circuit. Alternately or additionally, the parameters of the first PLL circuit may also be readjusted.

Method **400** illustrates one example method that may be used to adjust the parameters of PLL circuits in a clock multiplication and distribution system described herein. Multiple other types of method may also be used without departing from the scope of this disclosure.

FIG. **5** is a flowchart of an example method **500** of configuring a clock multiplication and distribution system, arranged in accordance with at least one embodiment described herein. The method **500** may be implemented, in some embodiments, by a clock multiplication and distribution system, such as the clock multiplication and distribution systems **100**, **200**, or **608** of FIGS. **1**, **2**, and **6**. Although illustrated as discrete blocks, various blocks may be divided into additional blocks, combined into fewer blocks, or eliminated, depending on the desired implementation.

The method **500** may begin at block **502**, where a first clock may be generated using a first phase-lock-loop circuit with a first integer divider circuit. The first clock may be based on a reference clock and the first clock.

In block **504**, a second clock may be generated using a second phase-lock-loop circuit with a second integer divider circuit. The second clock may be based on the first clock and the second clock. In some embodiments, a first multiplier value of the first integer divider circuit may be greater than a second multiplier value of the second integer divider circuit.

In block **506**, a measurement of jitter of the second clock may be obtained.

In block **508**, in response to the measurement of jitter being more than a particular jitter amount, one or more parameters of the first phase-lock-loop circuit may be adjusted to adjust the jitter of the second clock. In some embodiments, the one or more parameters of the first phase-lock-loop circuit may include one or more of a gain of an oscillator, a gain of a phase detector, a multiplier value of the first integer divider circuit, and a loop filter parameter.

In some embodiments, the acts of the block **508** may be performed in a hardware simulation. Alternately or additionally, the acts may be performed in hardware.

In some embodiments, the method **500** may further include adjusting one or more parameters of the second phase-lock-loop circuit to adjust the jitter of the second clock in response to the measurement of jitter being more than the particular jitter amount.

In some embodiments, the measurement of the jitter of the second clock may be a first measurement of jitter. In these and other embodiments, the method **500** may further include generating a third clock using a third phase-lock-loop circuit with a third integer divider circuit. The third clock may be based on the first clock and the third clock. The method **500** may further include obtaining a second measurement of jitter of the third clock. In response to the first measurement of jitter or the second measurement of jitter being more than the particular jitter amount, the method **500** may include adjusting one or more first parameters of the first phase-lock-loop circuit, one or more second parameters of the second phase-lock-loop circuit, and one or more third parameters of the third phase-lock-loop circuit until both the first measurement of jitter and the second measurement of jitter are less than the particular jitter amount.

FIG. **6** is a block diagram of a high-speed input/output port **600** (referred to herein as “the port **600**”) that includes an example clock multiplication and distribution system **608** (referred to herein as “the system **608**”), arranged in accordance with at least one embodiment described herein.

The system **608** may be analogous to the system **100** of FIG. **1** and may include a first PLL circuit **610** and a secondary PLL circuit **620**. The first PLL circuit **610** may include an open loop circuit portion **612** and a feedback loop **614** that includes an integer divider circuit **616**. The first PLL circuit **610**, the open loop circuit portion **612**, the feedback loop **614**, and the integer divider circuit **616** may be analogous to the first PLL circuit **110**, the open loop circuit portion **112**, the feedback loop **114**, and the integer divider circuit **116** of FIG. **1** and no further description is provided with respect to FIG. **6**.

The secondary PLL circuit **620** may include an open loop circuit portion **622** and a feedback loop **624** that includes an integer divider circuit **626**. The secondary PLL circuit **620**, the open loop circuit portion **622**, the feedback loop **624**, and the integer divider circuit **626** may be analogous to the secondary PLL circuit **120**, the open loop circuit portion **122**, the feedback loop **124**, and the integer divider circuit **126** of FIG. **1** and no further description is provided with respect to FIG. **6**.

The system **608** may further include a clock distribution network **630** that includes a repeater **632** that electrically couples the first PLL circuit **610** and the secondary PLL circuit **620**. The clock distribution network **630** and the repeater **632** may be analogous to the clock distribution network **130** and the repeater **132** of FIG. **1** and no further description is provided with respect to FIG. **6**.

The system **608** may be configured to generate a clock **626** based on a reference clock **606** using the first and secondary PLL circuits **610** and **620**. The reference clock **606** may be generated by a reference clock generator **602**. In some embodiments, the reference clock generator **602** may be an oscillating crystal circuit.

The clock **626** may be provided to a clocking unit **640** that may clock a data clock **634** using the clock **626**. The clocked data clock **634** may be output by the port **600** as a data stream **642**. Alternately or additionally, the data stream **642** may be received by the clocking unit **640** and may be clocked using the clock **626**. In some embodiments, the port **600** may be a port in a serial link between two communicating devices.

Modifications, additions, or omissions may be made to the port **600** without departing from the scope of the present disclosure. For example, the port **600** may include multiple lanes. In these and other embodiments, the system **608** may generate a separate clock for each of the lanes using the first PLL circuit **610** that provides a first clock to multiple other secondary PLL circuits.

Although the subject matter has been described in language specific to structural features and/or methodological acts, it is to be understood that the subject matter defined in the appended claims is not necessarily limited to the specific features or acts described above. Rather, the specific features and acts described above are disclosed as example forms of implementing the claims.

All examples and conditional language recited herein are intended as pedagogical objects to aid the reader in understanding the invention and the concepts contributed by the inventor to furthering the art, and are to be construed as being without limitation to such specifically recited examples and conditions. Although embodiments of the present inventions have been described in detail, it should be understood that the various changes, substitutions, and alterations could be made hereto without departing from the spirit and scope of the invention.

What is claimed is:

1. A clock multiplication and distribution system, comprising:
 - a physical first phase-lock-loop circuit that includes a first feedback loop with a first integer divider circuit, the first phase-lock-loop circuit configured to generate a first clock using a reference clock, wherein a frequency of the first clock is greater than a frequency of the reference clock;
 - a physical second phase-lock-loop circuit that includes a second feedback loop with a second integer divider circuit, the second phase-lock-loop circuit configured to generate a second clock using the first clock, wherein a frequency of the second clock is greater than the frequency of the first clock, and a bandwidth of the first phase-lock-loop circuit is greater than a bandwidth of the second phase-lock-loop circuit; and
 - a physical clock distribution network that electrically couples the first phase-lock-loop circuit and the second phase-lock-loop circuit.
2. The clock multiplication and distribution system of claim **1**, wherein the clock distribution network includes one or more clock repeaters between the first phase-lock-loop circuit and the second phase-lock-loop circuit.
3. The clock multiplication and distribution system of claim **1**, wherein the second phase-lock-loop circuit is one of a plurality of secondary stage phase-lock-loop circuits, wherein each of the secondary stage phase-lock-loop circuits includes a secondary stage feedback loop with a secondary stage integer divider circuit and is configured to generate a secondary stage clock using the first clock, and frequencies of the secondary stage clocks are approximately equal and greater than the frequency of the first clock.
4. The clock multiplication and distribution system of claim **1**, wherein a first multiplier value of the first integer divider circuit is greater than a second multiplier value of the second integer divider circuit.
5. The clock multiplication and distribution system of claim **1**, further comprising a control unit configured to adjust one or more parameters of each of the first phase-lock-loop circuit and the second phase-lock-loop circuit based on jitter of the second clock.

6. The clock multiplication and distribution system of claim 5, wherein the control unit is configured to adjust the one or more parameters of each of the first phase-lock-loop circuit and the second phase-lock-loop circuit until the jitter of the second clock is less than a first particular amount or a change in the jitter of the second clock is less than a second particular amount.

7. The clock multiplication and distribution system of claim 5, wherein the one or more parameters of the first phase-lock-loop circuit includes one or more of a gain of an oscillator, a gain of a phase detector, a multiplier value of the first integer divider circuit, and a loop filter parameter.

8. The clock multiplication and distribution system of claim 1, wherein the first phase-lock-loop circuit and the second phase-lock-loop circuit comprise analog phase-lock-loop circuits or all digital phase-lock-loop circuits.

9. The clock multiplication and distribution system of claim 1, wherein the clock multiplication and distribution system is included in a transceiver, the transceiver comprising:

a reference clock generator configured to generate the reference clock; and

a data port configured to communicate or receive data over a serial link, the data being clocked with the second clock.

10. A method, comprising:

generating, by way of hardware simulation using a computing system, a first clock using a first phase-lock-loop circuit with a first integer divider circuit, the first clock based on a reference clock and the first clock;

generating, by way of hardware simulation using the computing system, a second clock using a second phase-lock-loop circuit with a second integer divider circuit, wherein the second clock is based on the first clock and the second clock, and a bandwidth of the first phase-lock-loop circuit is greater than a bandwidth of the second phase-lock-loop circuit;

obtaining, by way of hardware simulation using the computing system, a measurement of jitter of the second clock; and

in response to the measurement of jitter being more than a particular jitter amount, adjusting, by way of hardware simulation using the computing system, one or more parameters of the first phase-lock-loop circuit to adjust the jitter of the second clock.

11. The method of claim 10, wherein in response to the measurement of jitter being more than the particular jitter amount, the method further comprising adjusting one or more parameters of the second phase-lock-loop circuit to adjust the jitter of the second clock.

12. The method of claim 10, wherein the one or more parameters of the first phase-lock-loop circuit includes one or

more of a gain of an oscillator, a gain of a phase detector, a multiplier value of the first integer divider circuit, and a loop filter parameter.

13. The method of claim 10, wherein a first multiplier value of the first integer divider circuit is greater than a second multiplier value of the second integer divider circuit.

14. The method of claim 10, wherein the measurement of jitter of the second clock is a first measurement of jitter, the method further comprising:

generating a third clock using a third phase-lock-loop circuit with a third integer divider circuit, the third clock based on the first clock and the third clock;

obtaining a second measurement of jitter of the third clock; and

in response to the first measurement of jitter or the second measurement of jitter being more than the particular jitter amount, adjusting one or more of: one or more first parameters of the first phase-lock-loop circuit, one or more second parameters of the second phase-lock-loop circuit, and one or more third parameters of the third phase-lock-loop circuit until both the first measurement of jitter and the second measurement of jitter are less than the particular jitter amount.

15. A clock multiplication and distribution system, comprising:

a physical first phase-lock-loop circuit that includes a first feedback loop with a first integer divider circuit, the first phase-lock-loop circuit configured to generate a first clock using a reference clock, wherein a frequency of the first clock is greater than a frequency of the reference clock;

a physical second phase-lock-loop circuit electrically coupled to the first phase-lock-loop circuit, wherein the second phase-lock-loop circuit includes a second feedback loop with a second integer divider circuit and is configured to generate a second clock using the first clock, wherein a frequency of the second clock is approximately equal or greater than the frequency of the first clock, and a bandwidth of the first phase-lock-loop circuit is greater than a bandwidth of the second phase-lock-loop circuit; and

a physical control unit electrically coupled to the first phase-lock-loop circuit and the second phase-lock-loop circuit, the control unit configured to adjust one or more parameters of the first phase-lock-loop circuit or of the second phase-lock-loop circuit to adjust a jitter of the second clock.

16. The clock multiplication and distribution system of claim 15, wherein a first multiplier value of the first integer divider circuit is greater than a second multiplier value of the second integer divider circuit.

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